TLC04/MF4A-50, TLC14/MF4A-100 BUTTERWORTH FOURTH-ORDER LOW-PASS SWITCHED-CAPACITOR FILTERS

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Low Clock-to-Cutoff-Frequency Ratio Error TLC04/MF4A-50 . . . ±0.8% TLC14/MF4A-100 . . . ±1%

- Filter Cutoff Frequency Dependent Only on **External-Clock Frequency Stability**
- Minimum Filter Response Deviation Due to **External Component Variations Over Time** and Temperature
- **Cutoff Frequency Range From 0.1 Hz** to 30 kHz, $V_{CC\pm} = \pm 2.5 \text{ V}$
- 5-V to 12-V Operation
- Self Clocking or TTL-Compatible and **CMOS-Compatible Clock Inputs**
- Low Supply-Voltage Sensitivity
- Designed to be Interchangeable With National MF4-50 and MF4-100

D OR P PACKAGE (TOP VIEW) 8 T FILTER IN **CLKIN** ην_{CC+} CLKR I 7 LS [6 AGND 3 5 | FILTER OUT VCC-

description

The TLC04/MF4A-50 and TLC14/MF4A-100 are monolithic Butterworth low-pass switched-capacitor filters. Each is designed as a low-cost, easy-to-use device providing accurate fourth-order low-pass filter functions in circuit design configurations.

Each filter features cutoff frequency stability that is dependent only on the external-clock frequency stability. The cutoff frequency is clock tunable and has a clock-to-cutoff frequency ratio of 50:1 with less than $\pm 0.8\%$ error for the TLC04/MF4A-50 and a clock-to-cutoff frequency ratio of 100:1 with less than $\pm 1\%$ error for the TLC14/MF4A-100. The input clock features self-clocking or TTL- or CMOS-compatible options in conjunction with the level shift (LS) terminal.

The TLC04C/MF4A-50C and TLC14C/MF4A-100C are characterized for operation from 0°C to 70°C. The TLC04I/MF4A-50I and TLC14I/MF4A-100I are characterized for operation from -40°C to 85°C. The TLC04M/MF4A-50M and TLC14M/MF4A-100M are characterized over the full military temperature range of -55°C to 125°C.

AVAILABLE OPTIONS

	CLOCK-TO-CUTOFF	PACKAGE						
TA	FREQUENCY RATIO	SMALL OUTLINE (D)	PLASTIC DIP (P)					
0°C to 70°C	50:1 100:1	TLC04CD/MF4A-50CD TLC14CD/MF4A-100CD	TLC04CP/MF4A-50CP TLC14CP/MF4A-100CP					
-40°C to 85°C	50:1 100:1	TLC04ID/MF4A-50ID TLC14ID/MF4A-100ID	TLC04IP/MF4A-50IP TLC14IP/MF4A-100IP					
−55°C to 125°C	50:1 100:1		TLC04MP/MF4A-50MP TLC14MP/MF4A-100MP					

The D package is available taped and reeled. Add the suffix R to the device type (e.g., TLC04CDR/MF4A-50CDR).



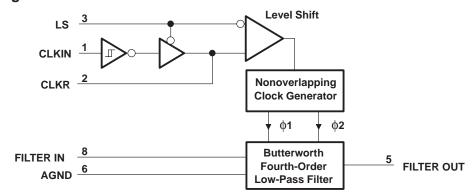
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TLC04/MF4A-50, TLC14/MF4A-100 **BUTTERWORTH FOURTH-ORDER LOW-PASS**

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functional block diagram



Terminal Functions

TERMINA	\L	1/0	DECORPTION
NAME	NO.	1/0	DESCRIPTION
AGND	6	ı	Analog ground. The noninverting input to the operational amplifiers of the Butterworth fourth-order low-pass filter.
CLKIN	1	I	Clock in. CLKIN is the clock input terminal for CMOS-compatible clock or self-clocking options. For either option, LS is at V_{CC-} . For self-clocking, a resistor is connected between CLKIN and CLKR and a capacitor is connected from CLKIN to ground.
CLKR	2	ı	Clock R. CLKR is the clock input for a TTL-compatible clock. For a TTL clock, LS is connected to midsupply and CLKIN can be left open, but it is recommended that it be connected to either V _{CC+} or V _{CC-} .
FILTER IN	8	I	Filter input
FILTER OUT	5	0	Butterworth fourth-order low-pass filter output
LS	3	I	Level shift. LS accommodates the various input clocking options. For CMOS-compatible clocks or self-clocking, LS is at V _{CC} and for TTL-compatible clocks, LS is at midsupply.
V _{CC+}	7	Ι	Positive supply voltage terminal
V _{CC} -	4	ı	Negative supply voltage terminal



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC+} (see Note 1)		±7\
	TLC04C/MF4A-50C, TLC14C/MF4A-100C 0°C t	
	TLC04I/MF4A-50I, TLC14I/MF4A-100I40°C t	to 85°C
	TLC04M/MF4A-50M, TLC14M/MF4A-100M55°C to) 125°C
Storage temperature range, T _{stq}	–65°C to) 150°C
Lead temperature 1.6 mm (1/16 inch) from	case for 10 seconds	260°C

NOTE 1: All voltage values are with respect to the AGND terminal.

recommended operating conditions

		TLC04/I	MF4A-50	TLC14/N	IF4A-100	UNIT	
		MIN	MAX	MIN	MAX	UNII	
Positive supply voltage, V _{CC+}		2.25	6	2.25	6	V	
Negative supply voltage, V _{CC} -		-2.25	-6	-2.25	-6	V	
High-level input voltage, VIH				2		V	
Low-level input voltage, V _{IL}			0.8		0.8	V	
Clock fraguency f (and Note 3)	$V_{CC\pm} = \pm 2.5 \text{ V}$	5	1.5 x 10 ⁶	5			
Clock frequency, f _{clock} (see Note 2)	V _{CC±} = ±5 V	5	2x10 ⁶	5	2x10 ⁶	Hz	
Cutoff frequency, f _{CO} (see Note 3)		0.1	40 x 10 ³	0.05	20 x 10 ³	Hz	
	TLC04C/MF4A-50C, TLC14C/MF4A-100C	0	70	0	70		
Operating free-air temperature, T _A	TLC04I/MF4A-50I, TLC14I/MF4A-100I	-40	85	-40	85	∘c	
	TLC04M/MF4A-50M, TLC14M/MF4A-100M	-55	125	-55	125		

NOTES: 2. Above 250 kHz, the input clock duty cycle should be 50% to allow the operational amplifiers the maximum time to settle while processing analog samples.

electrical characteristics over recommended operating free-air temperature range, $V_{CC+} = 2.5 \text{ V}$, $V_{CC-} = -2.5 \text{ V}$, $f_{clock} \le 250 \text{ kHz}$ (unless otherwise noted)

filter section

PARAMETER		TEST SOMBITIONS	TLC	04/MF4A	-50	TLC1	LINUT			
		TEST CONDITIONS	MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT	
Voo	Output offset voltage				25			50		mV
\/o.,	V _{OM} Peak output voltage	V _{OM+}	R _I = 10 kΩ	1.8	2		1.8	2		V
VOM	reak output voltage	VOM-	K[= 10 K22	-1.25	-1.7		-1.25	-1.7		V
Loo	Chart airquit autaut aurrent	Source	T _A = 25°C, See Note 4		-0.5			-0.5		mA
los	Short-circuit output current	Sink	1A = 25 C, See Note 4		4			4		IIIA
ICC	CC Supply current		f _{clock} = 250 kHz		1.2	2.25		1.2	2.25	mA

[‡] All typical values are at $T_A = 25$ °C.

NOTE 4: IOS(source) is measured by forcing the output to its maximum positive voltage and then shorting the output to the V_{CC}⁺ terminal IOS(sink) is measured by forcing the output to its maximum negative voltage and then shorting the output to the V_{CC}⁺ terminal.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

^{3.} The cutoff frequency is defined as the frequency where the response is 3.01 dB less than the dc gain of the filter.

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electrical characteristics over recommended operating free-air temperature range, V_{CC+} = 5 V, V_{CC-} = -5 V, $f_{clock} \le$ 250 kHz (unless otherwise noted)

filter section

PARAMETER		TEST	TLC	04/MF4 <i>A</i>	-50	TLC14/MF4A-100			UNIT	
		CONDITIONS		TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT	
Voo	Output offset voltage				150			200		mV
V Dook output voltage	V _{OM+}	P. = 10 kO	3.75	4.3		3.75	4.5		V	
VOM	Peak output voltage	V _{OM} -	$R_L = 10 \text{ k}\Omega$	-3.75	-4.1		-3.75	-4.1		V
la a	Chart aircuit autaut aurrent	Source	T _A = 25°C,		-2			-2		mΛ
los	Short-circuit output current	Sink	See Note 4		5			5		mA
Icc	CC Supply current		f _{clock} = 250 kHz		1.8	3		1.8	3	mA
ksvs	S Supply voltage sensitivity (see Figures 1 and 2)				-30			-30		dB

[†] All typical values are at $T_A = 25$ °C.

NOTE 4: $I_{OS(source)}$ is measured by forcing the output to its maximum positive voltage and then shorting the output to the V_{CC-} terminal. $I_{OS(sink)}$ is measured by forcing the output to its maximum negative voltage and then shorting the output to the V_{CC-} terminal.

clocking section

	PARAMETER	TEST	CONDITIONS	MIN	TYP†	MAX	UNIT	
\/	Positive going input throughold voltage		$V_{CC+} = 10 \text{ V},$	V _{CC} -=0	6.1	7	8.9	V
VIT+	Positive-going input threshold voltage		$V_{CC+} = 5 V$,	VCC-=0	3.1	3.5	4.4	V
\/. -	Negative-going input threshold voltage	CLKIN	$V_{CC+} = 10 V$,	VCC-=0	1.3	3	3.8	V
VIT-	Negative-going input tilleshold voltage	CLKIN	$V_{CC+} = 5 V$	VCC-=0	0.6	1.5	1.9	V
\/ı	Hysteresis voltage (V _{IT+} – V _{IT-})		$V_{CC+} = 10 V$,	VCC-=0	2.3	4	7.6	V
V _{hys}	S Hysteresis voltage (V + - V -)		$V_{CC+} = 5 V$,	VCC-=0	1.2	2	3.8	
Vон	High-level output voltage		$V_{CC} = 10 \text{ V}$	I _O = -10 μA	9			٧
VОН	Thigh level output voltage		$V_{CC} = 5 V$	10 = 10 μΑ	4.5			
VOL	Low-level output voltage		V _{CC} = 10 V	ΙΟ = 10 μΑ			1	V
VOL	Low level output voltage]	V _{CC} = 5 V	10 = 10 μΑ			0.5	Ů
	Input leakage current	CLKR	V _{CC} = 10 V	LS at midsupply,			2	μΑ
	input leakage culterit	CLKIK	$V_{CC} = 5 V$	T _A = 25°C			2	μΑ
			V _{CC} = 10 V	CLKR and CLKIN	-3	-7		mA
IO	Output current		$V_{CC} = 5 V$	shortened to V _{CC} -	-0.75	-2	·	IIIA
			$V_{CC} = 10 \text{ V}$	CLKR and CLKIN	3	7		mA
			V _{CC} = 5 V	shortened to V _{CC+}	0.75	2		

[†] All typical values are at $T_A = 25$ °C.



operating characteristics over recommended operating free-air temperature range, $V_{CC+} = 2.5 \text{ V}$, $V_{CC-} = -2.5 \text{ V}$ (unless otherwise noted)

DARAMETER	TEAT CONT	TEST CONDITIONS		04/MF4 <i>A</i>	\-50	TLC	ш		
PARAMETER	TEST CONL			TYP†	MAX	MIN	TYP	MAX	UNIT
Maximum clock frequency, f _{max}	See Note 2		1.5	3		1.5	3		MHz
Clock-to-cutoff-frequency ratio (f _{clock} /f _{co})	f _{clock} ≤ 250 kHz,	T _A = 25°C	49.27	50.07	50.87	99	100	101	Hz/Hz
Temperature coefficient of clock-to-cutoff frequency ratio	f _{clock} ≤ 250 kHz			±25			±25		ppm/°C
	$f_{CO} = 5 \text{ kHz},$ $f_{Clock} = 250 \text{ kHz},$ $T_A = 25^{\circ}\text{C}$	f = 6 kHz	-7.9	-7.57	-7.1				ı,
Frequency response above and below		f = 4.5 kHz	-1.7	-1.46	-1.3				dB
cutoff frequency (see Note 5)	f _{CO} = 5 kHz,	f = 3 kHz				-7.9	-7.42	-7.1	dB
	$f_{Clock} = 250 \text{ kHz},$ $T_A = 25^{\circ}\text{C}$	f = 2.25 kHz				-1.7	-1.51	-1.3	ив
Dynamic range (see Note 6)	T _A = 25°C			80			78		dB
Stop-band frequency attentuation at 2 f _{CO}	f _{clock} ≤ 250 kHz		24	25		24	25		dB
Voltage amplification, dc	f _{clock} ≤ 250 kHz,	$RS \le 2 k\Omega$	-0.15	0	0.15	-0.15	0	0.15	dB
Peak-to-peak clock feedthrough voltage	T _A = 25°C	_		5			5		mV

[†] All typical values are at $T_A = 25$ °C.

NOTES: 2. Above 250 kHz, the input clock duty cycle should be 50% to allow the operational amplifiers the maximum time to settle while processing analog samples.

- 5. The frequency responses at f are referenced to a dc gain of 0 dB.
- 6. The dynamic range is referenced to 1.06 V rms (1.5 V peak) where the wideband noise over a 30-kHz bandwidth is typically $106 \,\mu\text{V}$ rms for the TLC04/MF4A-50 and 135 μV rms for the TLC14/MF4A-100.

operating characteristics over recommended operating free-air temperature range, $V_{CC+} = 5 \text{ V}$, $V_{CC-} = -5 \text{ V}$ (unless otherwise noted)

DARAMETER	TEAT 00115	TEST CONDITIONS		04/MF4 <i>A</i>	\-50	TLC			
PARAMETER	TEST CONL			TYP†	MAX	MIN	TYP†	MAX	UNIT
Maximum clock frequency, f _{max}	See Note 2		2	4		2	4		MHz
Clock-to-cutoff-frequency ratio (f _{clock} /f _{co})	f _{Clock} ≤ 250 kHz,	$T_A = 25^{\circ}C$	49.58	49.98	50.38	99	100	101	Hz/Hz
Temperature coefficient of clock-to-cutoff frequency ratio	f _{clock} ≤ 250 kHz			±15			±15		ppm/°C
	$f_{CO} = 5 \text{ kHz},$ $f_{Clock} = 250 \text{ kHz},$ $T_A = 25^{\circ}\text{C}$	f = 6 kHz	-7.9	-7.57	-7.1				I.D.
Frequency response above and below		f = 4.5 kHz	-1.7	-1.44	-1.3				dB
cutoff frequency (see Note 5)	$f_{CO} = 5 \text{ kHz},$	f = 3 kHz				-7.9	-7.42	-7.1	dB
	$f_{clock} = 250 \text{ kHz},$ $T_A = 25^{\circ}\text{C}$	f = 2.25 kHz				-1.7	-1.51	-1.3	UD
Dynamic range (see Note 6)	T _A = 25°C			86			84		dB
Stop-band frequency attentuation at 2 f _{CO}	f _{clock} ≤ 250 kHz		24	25		24	25		dB
Voltage amplification, dc	f _{Clock} ≤ 250 kHz,	$RS \le 2 k\Omega$	-0.15	0	0.15	-0.15	0	0.15	dB
Peak-to-peak clock feedthrough voltage	T _A = 25°C			7			7		mV

[†] All typical values are at $T_A = 25$ °C.

NOTES: 2. Above 250 kHz, the input clock duty cycle should be 50% to allow the operational amplifiers the maximum time to settle while processing analog samples.

- 5. The frequency responses at f are referenced to a dc gain of 0 dB.
- 6. The dynamic range is referenced to 2.82 V rms (4 V peak) where the wideband noise over a 30-kHz bandwidth is typically 142 μ V rms for the TLC04/MF4A-50 and 178 μ V rms for the TLC14/MF4A-100.



TYPICAL CHARACTERISTICS

FILTER OUTPUT $vs \\ \text{SUPPLY VOLTAGE V}_{\text{CC+}} \, \text{RIPPLE FREQUENCY}$

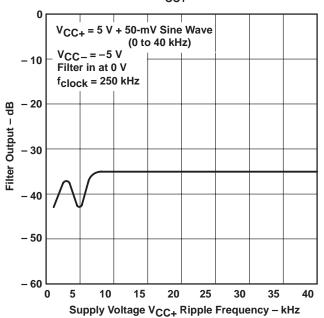


Figure 1

FILTER OUTPUT

SUPPLY VOLTAGE V_{CC}_ RIPPLE FREQUENCY

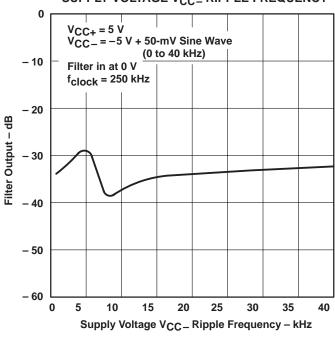


Figure 2



APPLICATION INFORMATION

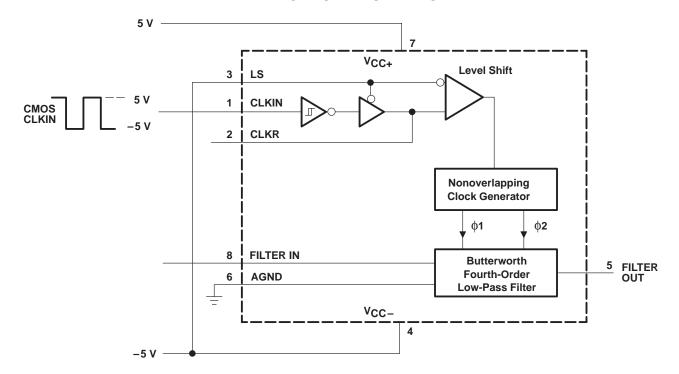


Figure 3. CMOS-Clock-Driven Dual-Supply Operation

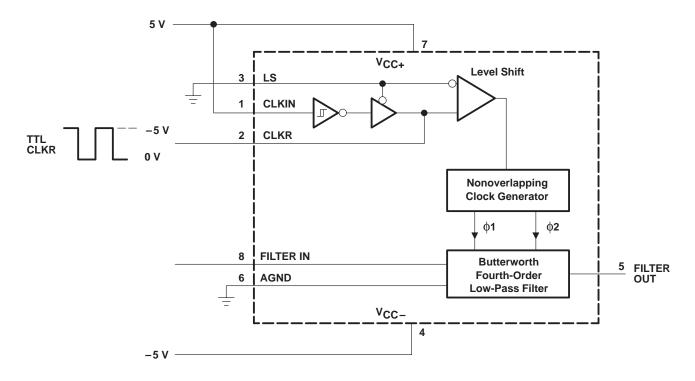


Figure 4. TTL-Clock-Driven Dual-Supply Operation



APPLICATION INFORMATION

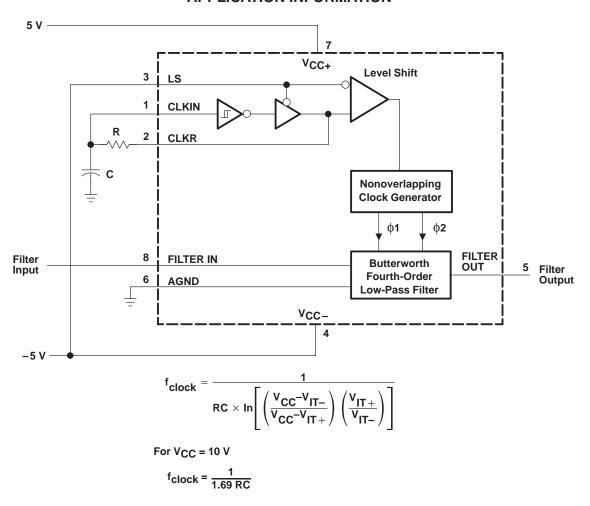
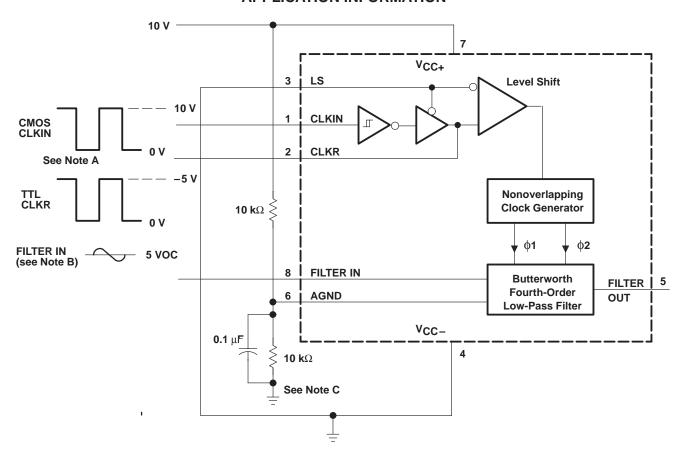


Figure 5. Self-Clocking Through Schmitt-Trigger Oscillator Dual-Supply Operation

APPLICATION INFORMATION

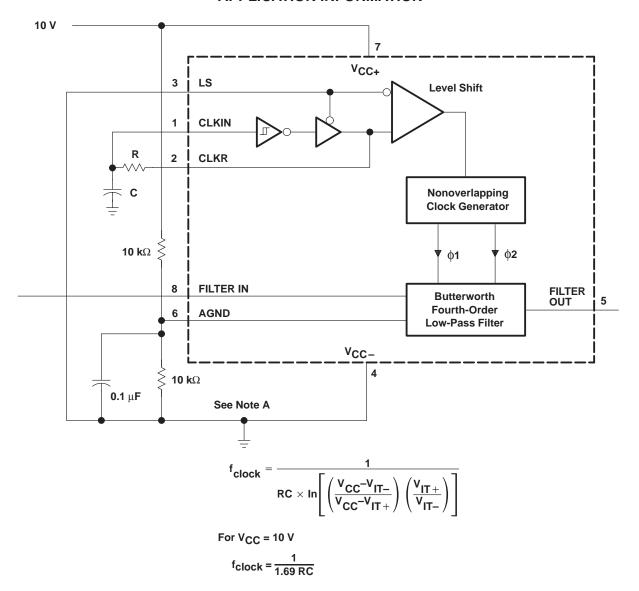


NOTES: A. The external clock used must be of CMOS level because the clock is input to a CMOS Schmitt trigger.

- B. The filter input signal should be dc-biased to midsupply or ac-coupled to the terminal.
- C. AGND must be biased to midsupply.

Figure 6. External-Clock-Driven Single-Supply Operation

APPLICATION INFORMATION



NOTE A: AGND must be biased to midsupply.

Figure 7. Self Clocking Through Schmitt-Trigger Oscillator Single-Supply Operation



APPLICATION INFORMATION

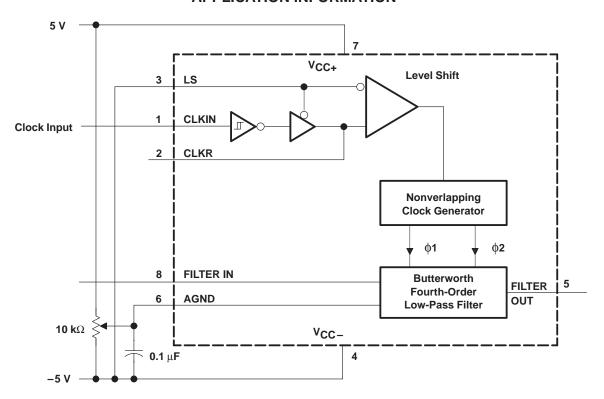


Figure 8. DC Offset Adjustment

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